



Library Information Update

FOR YOUR INFORMATION

The 1980 Workshop on Microprocessors and Education (TH0083-6) which appears in this issue of the Bulletin, is the second in a series of workshops that began in 1976. The first Workshop was held August 16-18, 1976 in Fort Collins, CO. A Proceedings was published by the Digital Systems Education (DISE) Project of the University of Pittsburgh's Electrical Engineering Department under the title, *DISE Workshop on Microprocessors and Education*. Information on the availability of copies of the 1976 Proceedings should be directed to: Electrical Engineering Department, University of Pittsburgh, Pittsburgh, PA 15261. Selected papers from the 1976 Workshop also appeared in a special issue of *Computer*, Vol. 10, No. 1, January 1977.

The Third International Conference: Security Through Science and Engineering (Sept. 23-26, 1980 in Berlin, West Germany) whose Proceedings (80CH1503-2) appears in the Conference Publications section of this issue of the Bulletin, was held for the first time in Edinburgh, Scotland on July 18-20, 1973. Its title was the **First International Electronic Crime Countermeasures Conference**. In 1977, the series continued with a conference held July 25-29 in Oxford, England. Again, its title changed and it was called the **International Conference on Crime Countermeasures—Science and Engineering**. Proceedings from both conferences were published through the Office of Engineering Services (OES) of the University of Kentucky (as is the 1980 volume) and are still available through them. The 1973 conference proceedings' publication number is UKY BU103 with LC number 76-371637. The 1977 volume's publication number is UKY BU113 with LC 78-621332. Write to this address for ordering information: OES Publications, College of Engineering, University of Kentucky, Lexington, Kentucky 40506.

Recent articles on microcomputing that have appeared in issues of *IEEE Transactions* and *Proceedings* are listed in a feature called "Access", which appears regularly in *IEEE Micro*, one of the new IEEE Computer Society magazines.

A 24-page program for SIGGRAPH '81 (8th Annual Conference on Computer Graphics and Interactive Techniques, Aug. 3-7, 1981 in Dallas, TX), sponsored by the Association for Computing Machinery, appears in the June 1981 issue of *Computer* (Vol. 14, No. 6) on pp. 101-124. It lists the courses and tutorials, technical program, registration information, and the future dates of this conference series.

TECHNICALLY—WRITE!, a home-study course available from IEEE, is meant to aid scientific and engineering professionals in communicating more effectively by teaching them to convey technical and business information in a clear and efficient way. For further information, contact IEEE Education Registrar, 345 East 47th St., New York, N.Y. 10017.

CONFERENCE NEWS

The first American Control Conference (ACC) is planned for June 14-16, 1982 in Arlington, VA. It will replace the annual Joint Automatic Control Conference (JACC) which is operated by the member societies of the American Automatic Control Council (AACC) on an alternating basis. Some of these member societies include IEEE, Instrument Society of America, ASME, American Institute of

Chemical Engineers, et al. Some of the topics that are planned for the technical program, which will cover control systems from theory to implementation, include linear and non-linear systems, large-scale systems, stability, deterministic and stochastic optimization, decentralized control, estimation and tracking, and resource allocation. Applications to be explored may include aerospace systems, chemical process control, manufacturing systems, energy systems, measurement and instrumentation, biomedical systems, and socioeconomic and environmental systems. A publication sponsored by the AACC is planned. The last JACC was held June 17-19, 1981 in Charlottesville, VA. The Proceedings (81CH1677-4) from this 1981 meeting will be announced in a future issue of the Bulletin.

ISSUES OF INTEREST

Computer Elements Committee Workshop, 9th IEEE Computer Society's, held June 22-25, 1980 in Vail, CO; sponsored by IEEE Computer Society's Computer Elements Committee; report in *Computer*, Vol. 14, No. 4, April 1981, pp. 77-80. \$6.00. **JH55921. THEME:** This report summarizes this Workshop's six sessions which covered the topics of processor technology, digital communications, memory technology, changing I/O, and impact on systems.

Five Ethical Dilemmas; IEEE Spectrum, Vol. 18, No. 6, June 1981, pp. 53-60. \$8.00. **JH53454. THEME:** Five ethical situations are presented with comments on how to solve them by a panel consisting of a philosopher, the Member Conduct Committee of IEEE, a lawyer, a manager, and five engineers plus the survey results from a randomly selected group of IEEE Spectrum readers who were asked to comment on the five situations.

IEEE Nuclear Standards; IEEE Power Engineering Review, Vol. PER-1, No. 5, May 1981, pp. 12-13. \$7.50. **JH56564. THEME:** This is a list of IEEE and ANSI/IEEE Standards concerned with nuclear power generation. The standard number and title are given.

Metric System: Its Status and Future; IEEE Spectrum, Vol. 18, No. 4, April 1981, pp. 60-63. \$8.00. **JH53439. THEME:** The progress of the United States towards conversion to the metric system is discussed.

Systematic Generation of Scientific Papers; Computer, Vol. 14, No. 5, May 1981, pp. 102-105. \$6.00. **JH55939. THEME:** A method for achieving a consistent style in writing scientific papers acceptable to most scientific journals is presented.

Technology—Alerting Index; IEEE Transactions on Electromagnetic Compatibility, Vol. EMC-23, No. 2, May 1981, pp. 53-57. \$10.00. **JH54791. THEME:** This editorial discusses a way of being alerted to technology about one year before publication through a special type of index.

VLSI Design and Debug Workshop, 1st IEEE, held May 25, 1980 in New York, NY; sponsored by IEEE Computer Society's Computer Elements Committee; summary in *Computer*, Vol. 14, No. 4, April 1981, page 78. \$6.00. **JH55921. THEME:** This Workshop dealt with debugging and diagnosing new VLSI designs and the process/yield variation and feedback aspects of the debug and diagnosis effort.

SERIALS CATALOG CARDS

The next two pages show several newly received cards

Conference on Precision Electromagnetic Measurements.
CPEM digest.
New York [etc.] Institute of Electrical and Electronics Engineers [etc.]
v. illus. 23-28 cm. biennial.
Title varies: 19 -66, CPEM program.
Vols. for sponsored by the Institute for Basic Standards; the Institute of Electrical and Electronics Engineers, Group on Instrumentation and Measurement; and the International Scientific Radio Union (19 -68 by the Union's U. S. Commission I: Radio Measurements Methods and Standards; 1970- by its U. S. National Committee).

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rev 71 r73c2, 75-23855

Conference on Precision Electromagnetic Measurements.
CPEM digest. (Card 2)

1. Electromagnetic measurements—Congresses. I. United States. Institute for Basic Standards. II. Institute of Electrical and Electronics Engineers. Group on Instrumentation and Measurement. III. International Scientific Radio Union. Commission I on Radio Measurements and Standards. IV. National Research Council. United States National Committee on URSI. V. Title. VI. Title: CPEM program.

QC670.C58 537 75-23855
rev 71 r73c2,
Library of Congress

Institute of Electrical and Electronics Engineers. Industry and General Applications Group.
IEEE conference record of [the] annual meeting; papers presented. 1st-6th; 1966-71.
New York.

6 v. ill. 28 cm.
Annual.
Continued by: IEEE Industry Applications Society. IEEE conference record of annual meeting.

1. Electric engineering—Congresses. I. Title.
TK5.I2 621.3 68-4739
MARC-S
Library of Congress r80jrev

IEEE Industry Applications Society.
IEEE conference record of annual meeting.

New York, Institute of Electrical and Electronics Engineers.

v. illus. 28 cm.

1. Electric engineering—Congresses.
TK5.I2 621.3 73-647500
Library of Congress 73 j2,

IEEE Industry Applications Society.
Conference record, IAS annual meeting. 10th-12th; 1975-77.
[New York, N.Y., Institute of Electrical and Electronics Engineers]
v. ill. 28 cm.
Annual.
Vols for sponsored by the IEEE Industry Applications Society, Chicago-Calumet Section.
Continues: IEEE Industry Applications Society. IEEE conference record of annual meeting of the IEEE Industry Applications Society.

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rev 810j, 80-640528
MARC-S

IEEE Industry Applications Society. Conference record, IAS annual meeting ... (Card 2)

Continued by: Conference record, Industry Applications Society, IEEE-IAS annual meeting, ISSN 0197-2618.
Key title: Conference record, IAS annual meeting, ISSN 0160-8592.

1. Electric engineering—Congresses. I. IEEE Industry Applications Society. Chicago-Calumet Section. II. IEEE Industry Applications Society. IAS annual meeting. III. Title.

TK5.I2 621.3'05 80-640528
MARC-S
Library of Congress r810j,

IEEE Industry Applications Society.
Conference record, Industry Applications Society, IEEE-IAS annual meeting. 13th- 1978-
[New York, N.Y., Institute of Electrical and Electronics Engineers]
v. ill. 28 cm.
Annual.
Vols. for 1978- sponsored by the IEEE Industry Applications Society, and IEEE Toronto Section.
Spine title: IEEE IAS annual meeting, 1978-
Continues: Conference record, IAS annual meeting, ISSN 0160-8592.

(Continued on next card)
rev 8007j, 80-640527
MARC-S

IEEE Industry Applications Society. Conference record, Industry Applications Society, IEEE-IAS annual meeting ... (Card 2)

Key title: Conference record, Industry Applications Society, IEEE-IAS annual meeting, ISSN 0197-2618.

1. Electric engineering—Congresses. 2. Electric power—Congresses. I. Institute of Electrical and Electronics Engineers. Toronto Section. II. IEEE Industry Applications Society. Industry Applications Society, IEEE-IAS annual meeting. III. IEEE Industry Applications Society. IEEE IAS annual meeting. IV. Title.

TK5.I2 621.3'05 80-640527
MARC-S
Library of Congress r8007j,

International Conference on Software Engineering.
Proceedings - International Conference on Software Engineering. 2d. 1976-
Long Beach, Calif. [etc.] IEEE Computer Society, [etc.]
v. ill. 28 cm.
Vols. for 1976- sponsored by IEEE Computer Society, <1976 with ACM Association for Computing Machinery and National Bureau of Standards; 1978- with National Bureau of Standards and ACM Sigsoft; 1979- with ACM Sigsoft and other similar organizations.
Continues: National Conference on Software Engineering. Proceedings of the National Conference on Software Engineering.

(Continued on next card)
rev 80-640758
MARC-S

International Conference on Software Engineering. Proceedings - International Conference on Software Engineering ... (Card 2)

Key title: Proceedings - International Conference on Software Engineering, ISSN 0270-5257.

1. Electronic digital computers—Programming—Congresses. 2. Computer programs - Congresses. 3. Programming languages (Electronic computers)—Congresses. I. IEEE Computer Society. II. Association for Computing Machinery. III. United States. National Bureau of Standards. IV. ACM Sigsoft. V. Key title.

QA76.6.N373a 001.64'2'05 80-640758
MARC-S

Library of Congress

International Symposium on Multiple-Valued Logic.
Proceedings - International Symposium on Multiple-Valued Logic. 1st- 1971-
[New York, etc., IEEE]

v. ill. 28 cm.
Annual.
Title varies slightly.
Symposia for 1971- sponsored by the Institute of Electrical and Electronics Engineers and other related bodies; 1979- by the IEEE Computer Society.
Key title: Proceedings - International Symposium on Multiple-Valued Logic, ISSN 0195-623X.

(Continued on next card)
rev 79-641110
MARC-S

77

International Symposium on Multiple-Valued Logic. Proceedings - International Symposium on Multiple-Valued Logic ... (Card 2)

1. Many-valued logic—Congresses. I. Institute of Electrical and Electronics Engineers. II. IEEE Computer Society. III. Key title.

QA9.45.I57a 511.3 79-641110
MARC-S

Library of Congress

77

Product Liability Prevention Conference.
Proceedings PLP. 1st-
1970-
Newark, New Jersey Institute of Technology.
v. ill. 28 cm. annual.
Conferences for 1970- sponsored by the North Jersey Section, American Society for Quality Control and others; by New Jersey Institute of Technology.
Indexes cumulative from 1970 included annually in vols. for

Key title: Proceedings PLP. Product Liability Prevention Conference, ISSN 0162-2010

1. Product safety—Congresses. 2. Products liability—United States—Congresses. I. New Jersey Institute of Technology. II. American Society for Quality Control. North Jersey Section. III. Key title.

TS175.P76a 658.5'6 78-641548
MARC-S

Library of Congress 70

Pulp and Paper Industry Technical Conference.
Pulp and paper industry technical conference; record.

New York, Institute of Electrical and Electronics Engineers.

v. illus. 28 cm. annual.

Conferences for sponsored by IEEE Technical Operations Committee.

1. Paper making and trade—Electric equipment—Congresses. I. Institute of Electrical and Electronics Engineers. II. Institute of Electrical and Electronics Engineers. Technical Operations Committee.

TS1109.P84 676'028 75-25186

Library of Congress 71 j2,

Pulp and Paper Industry Technical Conference.
IEEE Conference record of annual Pulp and Paper Industry Technical Conference. 1971-
[New York] Institute of Electrical and Electronics Engineers; available from IEEE Service Center.

v. ill. 29 cm.

Annual.
Conferences for 1971- sponsored by the IEEE Industry Applications Society, Technical Operations Committee, Pulp and Paper Industry and other groups.

Continues: Pulp and Paper Industry Technical Conference. Pulp and paper industry technical conference; record.

(Continued on next card)

74-136000
MARC-S

79

Pulp and Paper Industry Technical Conference. IEEE Conference record of annual Pulp and Paper Industry Technical Conference ... (Card 2)

Key title: IEEE Conference record of annual Pulp and Paper Industry Technical Conference, ISSN 0190-2172.

1. Paper making and trade—Electric equipment—Congresses. I. Institute of Electrical and Electronics Engineers. II. IEEE Industry Applications Society. III. Institute of Electrical and Electronics Engineers. Technical Operations Committee. IV. Key title.

TS1109.P84 675 74-136000
MARC-S

Library of Congress

79

ACRONYMS FOR NON-IEEE ORGANIZATIONS LISTED AS OTHER SPONSORS

The following acronyms should be added to the list "Acronyms For Societies and Organizations Listed as Other Sponsors," which appeared in the January 1981 issue of the Supplement:

ACU	-- Asociacion de Calculo Universitario
AEI	-- Italian Electrotechnical Assn. (Associazione Elettrotecnica ed Elettronica Italiana)
AFCET	-- Association Française pour la Cybernétique Economique et Technique
AICA	-- Associazione Italiana per il Calcolo Automatica
ASE	-- Association Suisse Des Electriciens
AVS	-- American Vacuum Society
CIEA	-- Centro de Investigacion y De Estudios Avanzados
CNET	-- Centre National d'Etudes des Télécommunications
CNRS	-- Centre National de la Recherche Scientifique
DAGM	-- Deutsche Arbeitsgemeinschaft fuer Mustererkennung
EPFL	-- Swiss Federal Institute of Technology (Ecole Polytechnique Fédérale, Lausanne)
EPS	-- European Physical Society
ERO	-- European Research Office

ESC	-- European Society of Cardiology
ETHZ	-- Eidgenössische Technische Hochschule, Zürich
GESO	-- Groupement De L'Electronique De Suisse Occidentale
IAPR	-- International Association for Pattern Recognition
IAU	-- International Astronomers Union
IFIP	-- International Federation for Information Processing
IIC	-- Istituto Internazionale delle Comunicazioni
IIT	-- Illinois Institute of Technology
INRIA	-- Institut National de Recherche en Informatique et en Automatique
INTELSAT	-- International Telecommunications Satellite Organization
IPS	-- Israel Physical Society
ISHM	-- International Society for Hybrid Microelectronics
IUPAP	-- International Union of Pure and Applied Physics
IUVSTA	-- International Union of Vacuum Science Technique & Applications
JPL	-- Jet Propulsion Lab
LRI	-- Laboratoire de Recherche en Informatique, Paris-Sud University, Orsay
NIH	-- National Institute of Health
NUPAP	-- National Union of Pure & Applied Physics
SEV	-- Schweizerischer Elektrotechnischer Verein
SIAM	-- Society for Industrial and Applied Mathematics

CONFERENCE ACRONYMS

The acronym that is used to refer to a conference in the annual *Index to IEEE Publications* is, in some cases, different from the one that the conference itself uses. This is a list of such conferences, the acronyms used by IEEE, and the acronyms that the conference itself uses.

Conference	IEEE Acronym	Conference Acronym
IEEE Conference on Decision and Control including the Symposium on Adaptive Processes (SAP)	DECC	CDC
IEEE Delaware Bay Computer Conference	MICRODEL	MICRO-DELCON
IEEE International Automatic Testing Conference	AUTOTEST	AUTOTESTCON
IEEE Southeastcon	SECON	SOUTHEASTCON
International Conference on Pattern Recognition	PATREC	ICPR
International Conference on Software Engineering	SOFTE	ICSE
International Symposium on Computer Architecture	COMPARC	ISCA
Symposium on Computer Application in Medical Care	CAMC	SCAMC

CONFERENCE HISTORIES

The Conference on the Application of Accelerators in Research and Industry (6th, 1980, JH55251; listed in this issue of the Bulletin under Conf. Publications) has gone through a considerable number of title changes since it began in 1968. This is a short history of the Conference and its publications pre-1980:

1st: April 1968 in Oak Ridge, TN. **Oak Ridge Conference on the Use of Small Accelerators for Teaching and Research.** Proceedings available from NTIS(a). No. CONF-680411, \$32.00.

2nd: March 23-25, 1970 in Oak Ridge, TN. **Oak Ridge Conference on the Use of Small Accelerators for Teaching and Research.** Proceedings available from NTIS. No. CONF-700322, \$32.00.

3rd: Oct. 21-27, 1974 in Denton, TX. **Conference on Application of**

Small Accelerators. Proceedings available from NTIS. Vol. 1: *The Use of Small Accelerators in Research and Teaching*, No. CONF-741040-P1, \$33.50. Vol. 2: *Industrial Applications of Small Accelerators*, No. CONF-741040-P2, \$27.50.

4th: Oct. 27-29, 1976 in Denton, TX. **Conference on the Scientific & Industrial Applications of Small Accelerators.** Proceedings no longer available but originally were through IEEE, No. 76CH1175-9.

5th: Nov. 6-8, 1978 in Denton, TX. **Conference on the Applications of Small Accelerators in Research and Industry.** Proceedings available from IEEE (b). Published in *IEEE Transactions on Nuclear Science*, Vol. NS-26, No. 1, Pt. 2, Feb. 1979, JH49999, \$20.00.

(a) NTIS [National Technical Information Service], Sales Dept., Port Royal Rd., Springfield, VA 22161

(b) IEEE Service Center, 445 Hoes Lane, Piscataway, NJ 08854